

<b>INFORMATION DISCLOSURE CITATION</b> (Use several sheets if necessary)				ATTY DOCKET NO.		APPLICATION NO.	
				TROLOGY 02.02		10/536.576	
				APPLICANT(S)			
				Szwajkowski et al.			
				FILING DATE		GROUP ART UNIT	
				February 6, 2006			

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
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/HL/	6,304,330	10.16.2001	Millerd et al.	356	521		
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/HL/	2003/0095264	05/2003	Ruchet	356	491		

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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
/HL/	DE 196 52 113	18.06.1998	Germany				
/HL/	WO 2004/051182	17.06.2004	PCT	G01B	9/02		

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/HL/		Hettwer, et al., "Three Channel Phase-Shifting Interferometer Using Polarization-Optics and a Diffraction Grating", The International Society for Optical Engineering, Optical Engineering, Vol. 39, pps. 960-966, April 2000 (abstract only).	
/HL/		Nakadate et al., "Real-Time Fringe Patter Processing and its Applications", Proc. of SPIE, Vol. 2544, pps. 74-86, June 1995 (abstract only).	

EXAMINER /Hwa Lee/	DATE CONSIDERED 12/22/2007
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. PATENT APPLICATION PUBLICATIONS							
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FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

  

OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>			
/HL/			Sivakumar, et al., "Large Surface Profile Measurement with Instantaneous Phase-Shifting Interferometry", Optical Engineering, February 2003, Vol. 42, Issue 2, pps. 367-372 (abstract only).
/HL/			Koliopoulos, Chris L., "Simultaneous Phase-Shift Interferometer", Proceedings of SPIE, Vol. 1531, Advanced Optical Manufacturing and Testing II, 1992, pps. 119-127.

  

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